



APMC 2025

2025 ASIA-PACIFIC MICROWAVE CONFERENCE

DEC 2 - 5, 2025 | ICC JEJU, Jeju Island, Korea

Session Title:

[FB2] Recent Advances in Instrumentation and Device Measurements

Session Date:

December 5 (Fri.), 2025

Session Time:

10:30-12:10

Session Room:

Room B (Halla B)

[FB2-1]

10:30-10:50

Challenges for High-Datarate Chip-to-Chip Interconnects Using Organic Interposer Materials for Heterogeneous Chiplet Systems Up to 110 GHz

Jens Loeffler (Friedrich-Alexander-Universität Erlangen Nürnberg, Germany); Manuel Koch and Sascha Breun (Friedrich-Alexander-Universität Erlangen-Nürnberg, Germany); Robert Weigel (Friedrich-Alexander Universität Erlangen-Nürnberg, Germany); Norman Franchi (Friedrich-Alexander-Universität Erlangen-Nürnberg, Germany)

[FB2-2]

10:50-11:10

Open-Loop Active Load-Pull Setup Using the ZCU216 Radio Frequency System-on-Chip

Iaroslav Shilinkov (Chalmers University of Technology, Sweden); Rob Maaskant (CHALMERS, Sweden); Gregor Lasser (Chalmers University of Technology, Sweden)

[FB2-3]

11:10-11:30

Transformation Response Analysis of Wideband Impedance Transforming Test Fixtures in Load-Pull Measurement Setups

Lida Kouhalvandi (Dogus University, Turkey); Osman Ceylan (Maury Microwave, USA)

[FB2-4]

11:30-11:50

Four-Port Probe Stations and SOLR Calibration Standard Design Up to 125 GHz on 28 nm CMOS

Dipankar Shakya (New York University, USA); Theodore Rappaport (New York University & NYU WIRELESS, USA); Ethan Shieh and Michael E. Knox (NYU WIRELESS, USA); Hamed Rahmani (New York University, USA); Davood Shahrjerdi (NYU WIRELESS, USA); Mingjun Ying (New York University & NYU WIRELESS, USA); Kimberly Fan and Matt Lu (MPI Corporation, USA); Andrej Rumiantsev (MPI Corporation, Germany); Vince Malette (MPI Corporation, USA); Gavin Fisher, Giancarlo De Chirico, Pratik Ghate and Shean McMahon (Formfactor Inc., USA)

[FB2-5]

11:50-12:10

Deep Learning Based Phase Calibration for Enhanced Beam Control Accuracy

Nam Jik Kim (Chung-Ang University, Korea (South)); Gilsu Jeong (University of Electronics Engineering & Chung-Ang University, Korea (South)); Han Lim Lee (Chung-Ang University, Korea (South))